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**1 Two new techniques for identifying opens on printed circuit boards: analog junction test, and radio frequency induction test**

*Wrinn, J.;*

Test Conference, 1995. Proceedings., International , 21-25 Oct. 1995  
 Pages:927

[\[Abstract\]](#)   [\[PDF Full-Text \(88 KB\)\]](#)   **IEEE CNF**

**2 Image mosaicing for rolled fingerprint construction**

*Ratha, N.K.; Connell, J.H.; Bolle, R.M.;*

Pattern Recognition, 1998. Proceedings. Fourteenth International Conference on , Volume: 2 , 16-20 Aug. 1998  
 Pages:1651 - 1653 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(424 KB\)\]](#)   **IEEE CNF**

**3 RF induction and analog junction techniques for finding opens**

*McElfresh, B.K.;*

Test Conference, 1997. Proceedings., International , 1-6 Nov. 1997  
 Pages:275

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